



Doosan Heavy Industries & Construction

Doosan Practice of V&V and Testing in FPGA Development Process

Oct 16, 2015

Shanghai, China



Table of Contents

1. Introduction

- . V&V in FPGA Development Process
: NUREG/CR-7006, IEC62566

2. V&V and Testing

- . Document Evaluation and Static Verification
- . Component Test
- . Integration Test
- . System Test

3. Recommendation

Table of Contents

1. Introduction

- . V&V in FPGA Development Process
: NUREG/CR-7006, IEC62566

2. V&V and Testing

- . Document Evaluation and Static Verification
- . Component Test
- . Integration Test
- . System Test

3. Recommendation

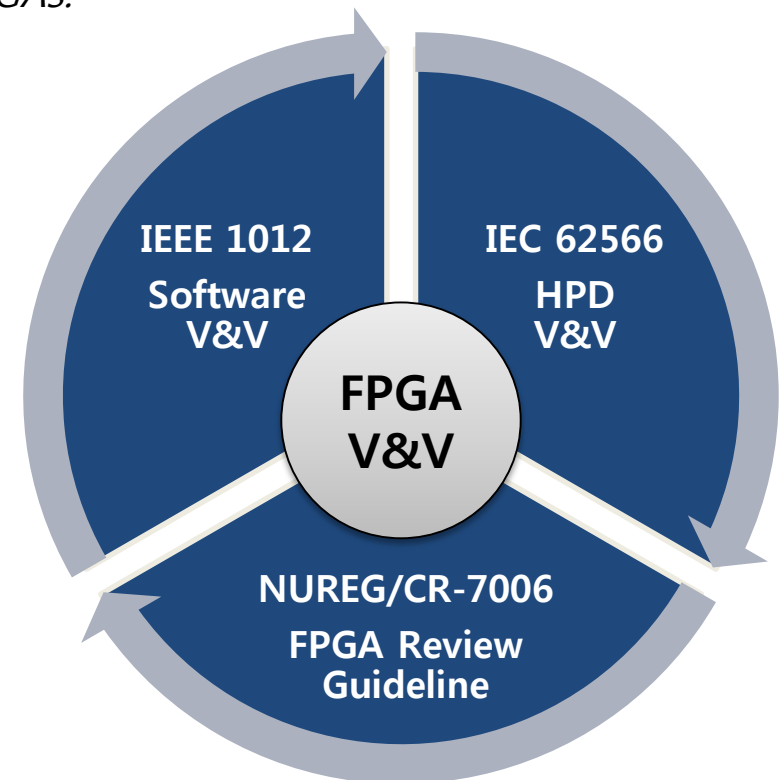
I. Introduction

1-1. V&V in FPGA Development Process

- FPGA has mixed characteristics of hardware and software
- FPGA V&V is hard to be achieved with IEEE Std. 1012 (a basis for NPP software V&V)
 - *[NUREG/CR-7006] IEEE-1002-2004 is a software-only standard, and it can not be directly applied to V&V process for FPGA-based systems. Even though the top level V&V processes and underlying activities are generic and can be used for FPGAs, the low level tasks are software specific, and not directly applicable to FPGAs.*

→ Harmonized existing FGPA standards and technologies into IEEE Std. 1012-based SDLC (Software Development Life Cycle)

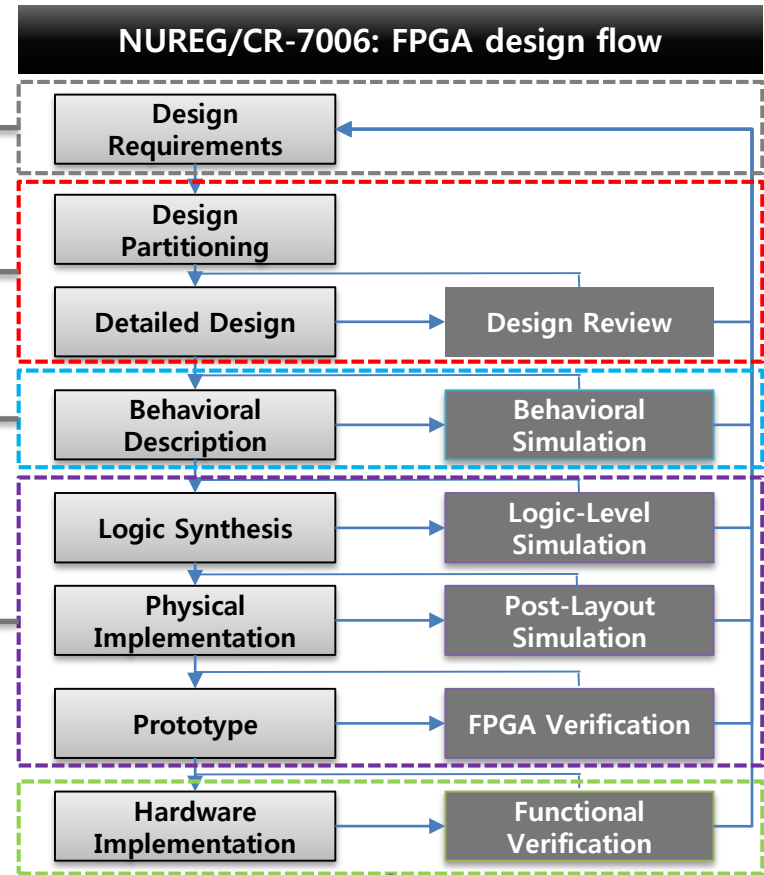
- **IEEE Std. 1012** : Standard for Software Verification and Validation
- **NUREG/CR-6007** : Review Guidelines for Field-Programmable Gate Arrays in Nuclear Power Plant Safety Systems
- **IEC 62566** : Nuclear power plants – Instrumentation and control important to safety – Development of HDL-programmed integrated circuits for systems performing category A functions



I. Introduction

1-2. Application of NUREG/CR-7006 Review Guidelines for FPGA in NPPS

NUREG/CR-7006	Application Notes
Chapter 3. FPGA DESIGN ENTRY METHODS	<ul style="list-style-type: none"> Discuss design practices that can lead to unreliable FPGA design, and therefore should be avoided → Defined syntax rules for VHDL/Verilog FPGA code considering the practices. → Check the conformance through static analysis and inspection in the implementation phase
Chapter 4. FPGA DESIGN METHODOLOGIES	<ul style="list-style-type: none"> Discuss low-level tasks for FPGA design and verification → Harmonized the tasks into IEEE-1012 based V&V process.



I. Introduction

1-3. Application of IEC 62566 : HPD※ Verification

IEC 62566 Section 9 HPD Verification	Application Notes
9.1 General	<ul style="list-style-type: none"> Independent V&V team
9.2 Verification plan	<ul style="list-style-type: none"> Software V&V plan in the concept phase
9.3 Verification of the use of the pre-developed items	<ul style="list-style-type: none"> Original software
9.4 Verification of the design and implementation	<ul style="list-style-type: none"> SRS, SDD document evaluation
9.5 Test-benches	<ul style="list-style-type: none"> Test-benches to fulfil requirement and path coverage
9.6 Test Coverage	<ul style="list-style-type: none"> Path/Branch coverage for Component Test Requirement coverage for Integration Test
9.7 Test Execution	<ul style="list-style-type: none"> Behavioral simulation using test benches Timing simulation
9.8 Static verification	<ul style="list-style-type: none"> NUREG/CR-7006 based type and syntax checking

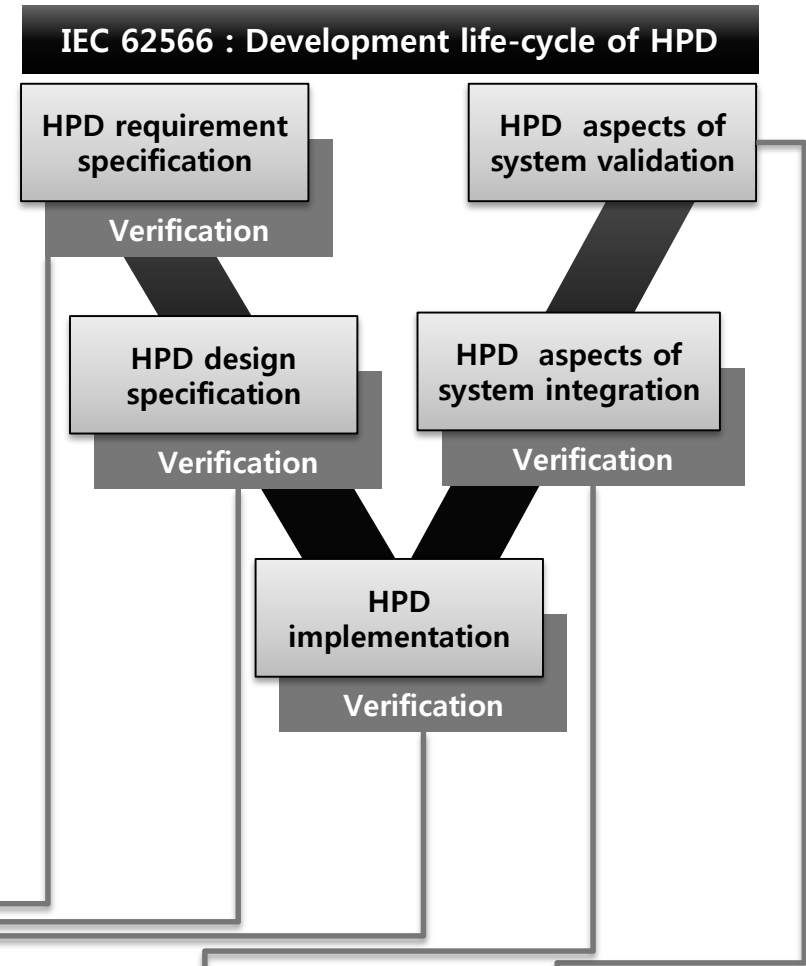


Table of Contents

1. Introduction

- . V&V in FPGA Development Process
: NUREG/CR-7006, IEC62566

2. V&V and Testing

- . Document Evaluation and Static Verification: V&V
- . Component Test
- . Integration Test
- . System Test

3. Recommendation

2. V&V and Testing

2-1. Document Evaluation and Static Verification



- Evaluates design documents and HDL-program code using BTP-14[※], IEEE Std. 1012, and NUREG/CR-7006

SRS/SDS/Code Documentation					Code
BTP-14		IEEE Std. 1012			NUREG/CR-7006
Functional Characteristics	Process Characteristics	Traceability Analysis	Document Evaluation	Interface Analysis	FPGA DESIGN ENTRY METHODS
Accuracy	Completeness	Correctness	Correctness	Correctness	Reliability
Functionality	Consistency	Consistency	Consistency	Consistency	Robustness
Reliability	Correctness	Completeness	Completeness	Completeness	Traceability
Robustness	Style	Accuracy	Accuracy	Accuracy	Maintainability
Safety	Traceability		Readability	Testability	
Security	Unambiguity		Testability		
Timing	Verifiability				

➔ Verification through inspection and walkthrough using checklist

※ USNRC-0800 Standard Review Plan: Chapter 7. Instrumentation and Controls BTP-14

2. V&V and Testing:Micro-semi(Libero)

2-2. Component Test

Requirement Verification

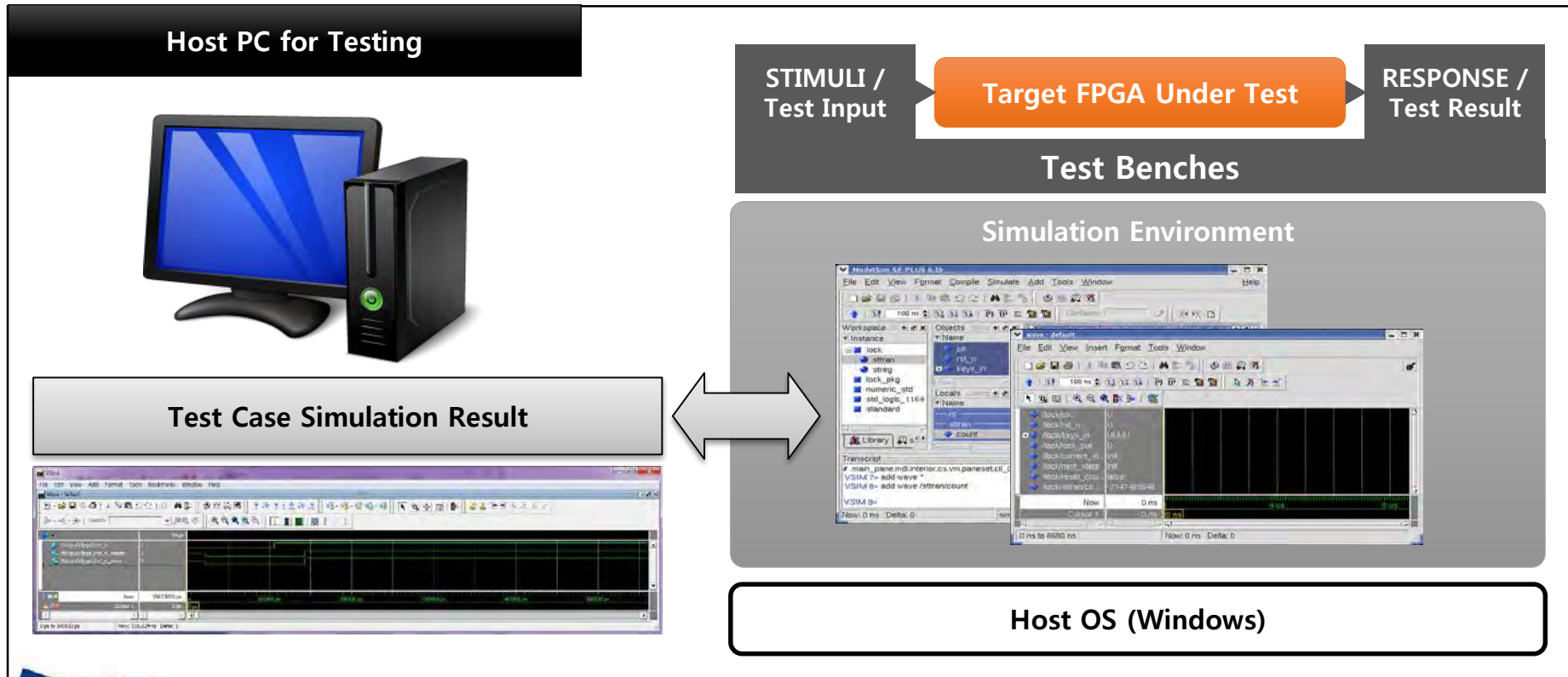
Design Verification

Code Inspection / Component Test

Integration (card, module) Test

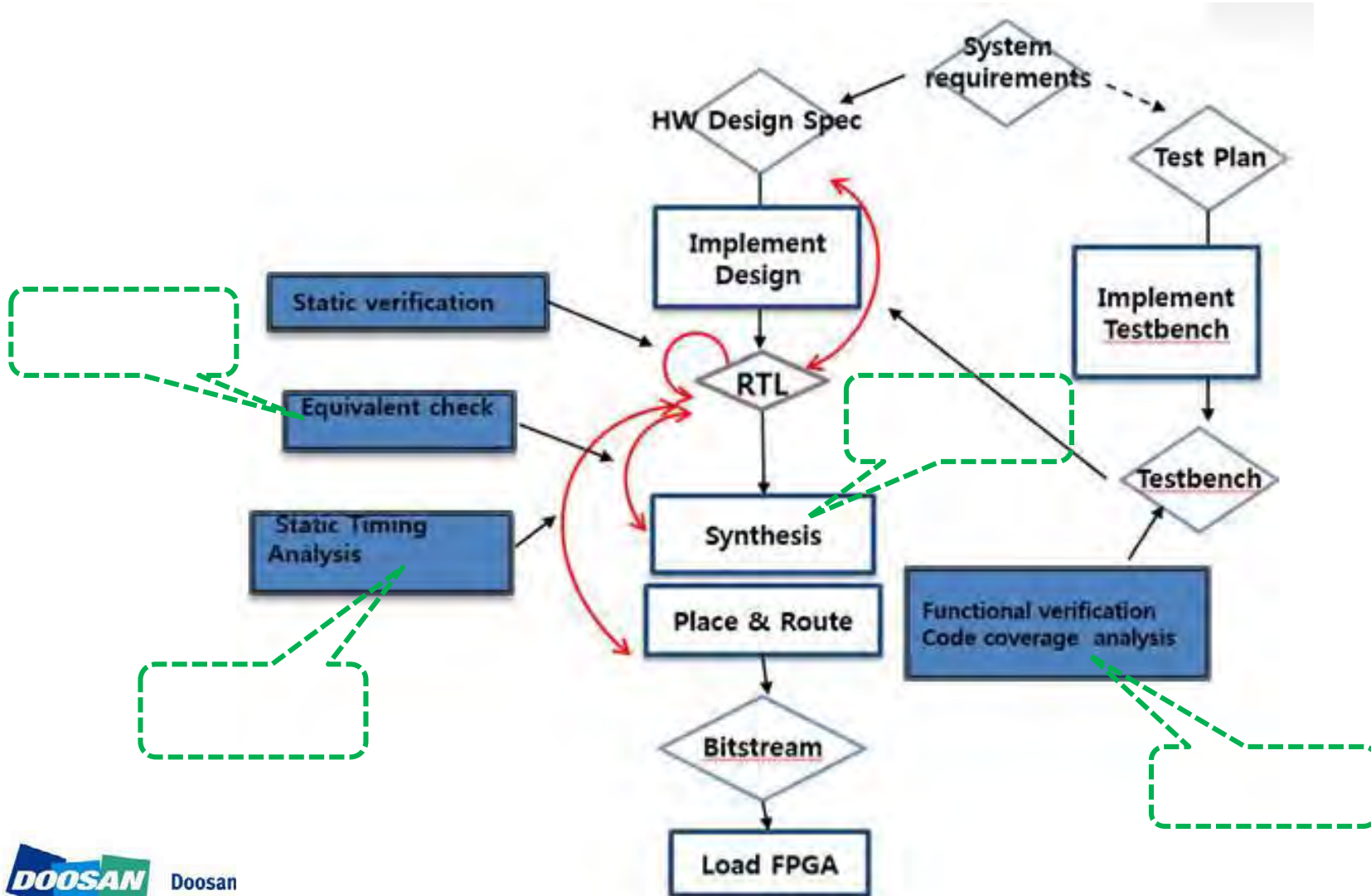
System (FPGA controller) Test

- Behavior/timing simulation was performed on RTL/HDL code
- Test criteria : Path coverage, Requirement coverage
- Test environment : Host PC-based Simulation Environment



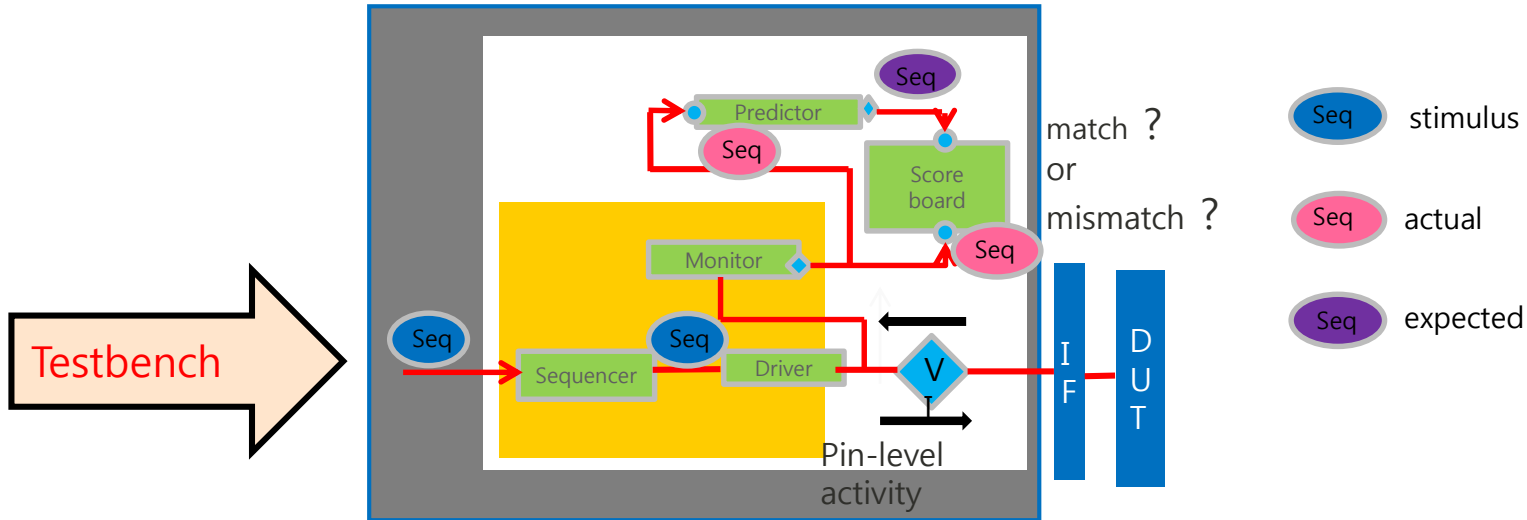
2. V&V and Testing

2-2. Component Test



2. V&V and Testing

2-2. Component Test



● The Result of Functional Test

```

>> |-----cldiol_bus_rxa-->reset/cld_errst-----|
>> | SIGNAL          || status || value || expt || p/np || SWR ||
>> | reset           || input  || 1     || n/a  || n/a  || 15  ||
>> | scl_clk         || input  || 1     || n/a  || n/a  || 15  ||
>> | SLOD_POS        || input  || 0     || n/a  || n/a  || 15  ||
>> | SROD            || input  || 1111  || n/a  || n/a  || 15  ||
>> | id_module       || input  || 4801  || n/a  || n/a  || 15  ||
>> | sel_bus         || output || 0     || 0    || Pass || 15  ||
>> | err_sel_bus     || output || 0     || 0    || Pass || 15  ||
>> | err_proc        || output || 0     || 0    || Pass || 15  ||
>> | err_errk        || output || 0     || 0    || Pass || 15  ||
>> | err_tx_mocm     || output || 0     || 0    || Pass || 15  ||
>> | norm_op         || output || 0     || 0    || Pass || 15  ||
>> | cld_errst       || output || 0     || 0    || Pass || 15  ||
>> | en_snd_aec      || output || 0     || 0    || Pass || 15  ||
>> | set_mon_time    || output || 0     || 0    || Pass || 15  ||
>> | set_en_tx_diag  || output || 0     || 0    || Pass || 15  ||
>> | set_en_tx_ch    || output || 0     || 0    || Pass || 15  ||
>> | set_en_tx_diag  || output || 0     || 0    || Pass || 15  ||
>> | set_en_tx_ch    || output || 0     || 0    || Pass || 15  ||
>> | set_tx_addr0=3  || output || 0000  || 0000  || Pass || 15  ||
>> | set_tx_addr0=3  || output || 0000  || 0000  || Pass || 15  ||
>> | set_tx_dlen0=3  || output || 00    || 00    || Pass || 15  ||
>> | set_tx_dlen0=3  || output || 0000  || 0000  || Pass || 15  ||
>> | set_tx_addr0=3  || output || 0000  || 0000  || Pass || 15  ||
>> | set_tx_addr0=3  || output || 00    || 00    || Pass || 15  ||
>> | set_tx_dlen0=3  || output || 00    || 00    || Pass || 15  ||
>> | set_tx_dlen0=3  || output || 0     || 0     || Pass || 15  ||
>> | drdy_tx_dqm     || output || 0     || 0     || Pass || 15  ||
  
```

(value : actual I/O, expt: expected value, p/np : True/False)

● The Result of Code Coverage Analysis

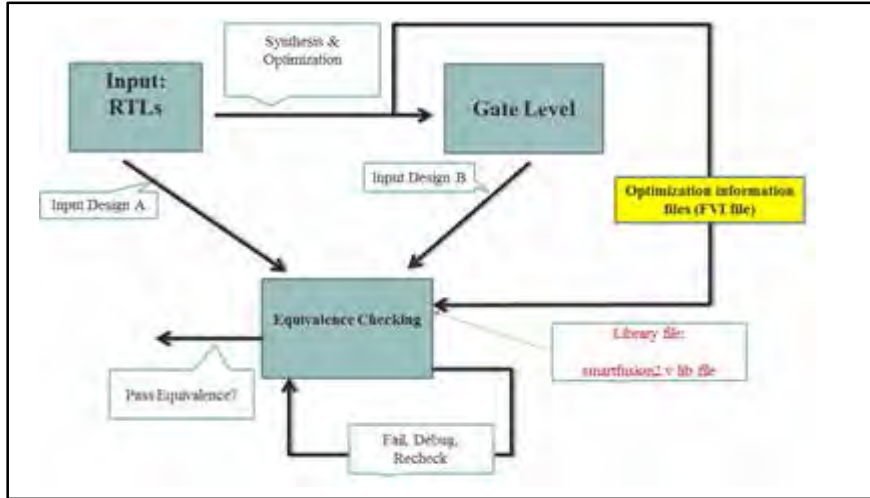
	Total coverage	Stmt count	Stmts hit	Stmts	Stmt %	Stmt gap	Branch	Branches	Branches miss
	93.7%	63	62	1	98.4%		108	107	1
	50.0%								
	95.1%	45	44	1	97.8%		108	107	1
	80.4%	5	4	1	80%		12	11	1
diag0		5	5	0	100%		12	12	0
diag1		5	5	0	100%		12	12	0
diag2		5	5	0	100%		12	12	0
diag3		5	5	0	100%		12	12	0
diag4		5	5	0	100%		12	12	0
diag5		5	5	0	100%		12	12	0
diag6		5	5	0	100%		12	12	0
diag7		5	5	0	100%		12	12	0

2. V&V and Testing:detail output example

2-2. Component Test



- Method of Equivalent Checking



- The Result of Equivalent Checking (Ex : Data Link Communication Module)

(Number of Test Items : 1336, Number of Equivalent Items : 1336)

- Result of Static Timing Analysis (Using SmartTime Tool)

Source Pin	Sink Pin	Delay (ns)	Slack (ns)	Arrival (ns)	Required (ns)
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T0	1.831	0.907	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T1	1.928	0.446	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T2	1.928	0.446	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T3	1.928	0.447	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T4	1.928	0.554	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T5	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T6	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T7	1.928	0.688	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T8	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T9	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T10	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T11	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T12	1.928	0.833	1.928	0.928
CLIP001_SBUS_ARC_DAG_B/STATUS_ARC_CONTROL_V	CLIP001_SBUS_T13	1.928	0.833	1.928	0.928

2. V&V and Testing

2-3. Integration Test

Requirement Verification

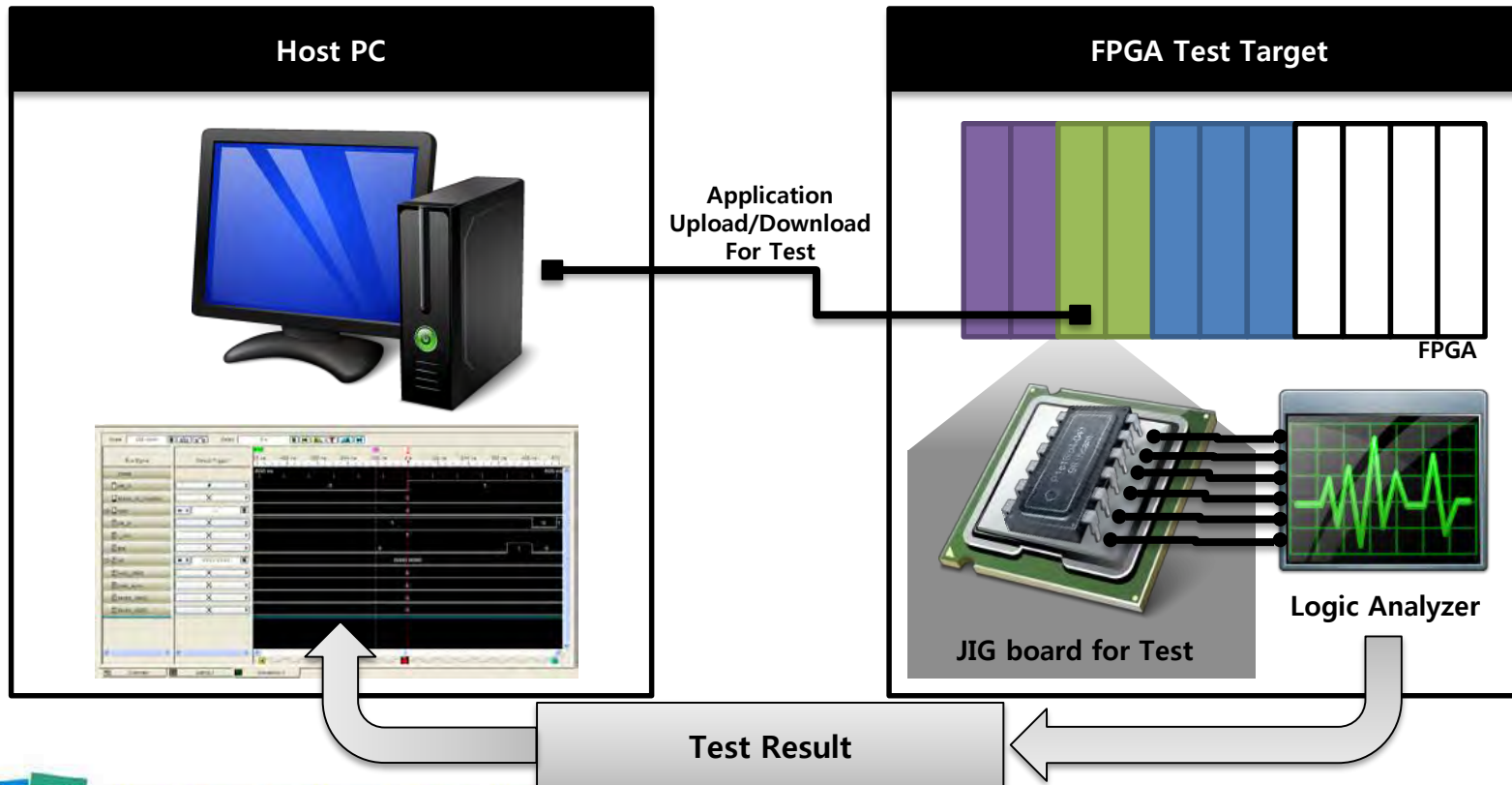
Design Verification

Code Inspection / Component Test

Integration (card, module) Test

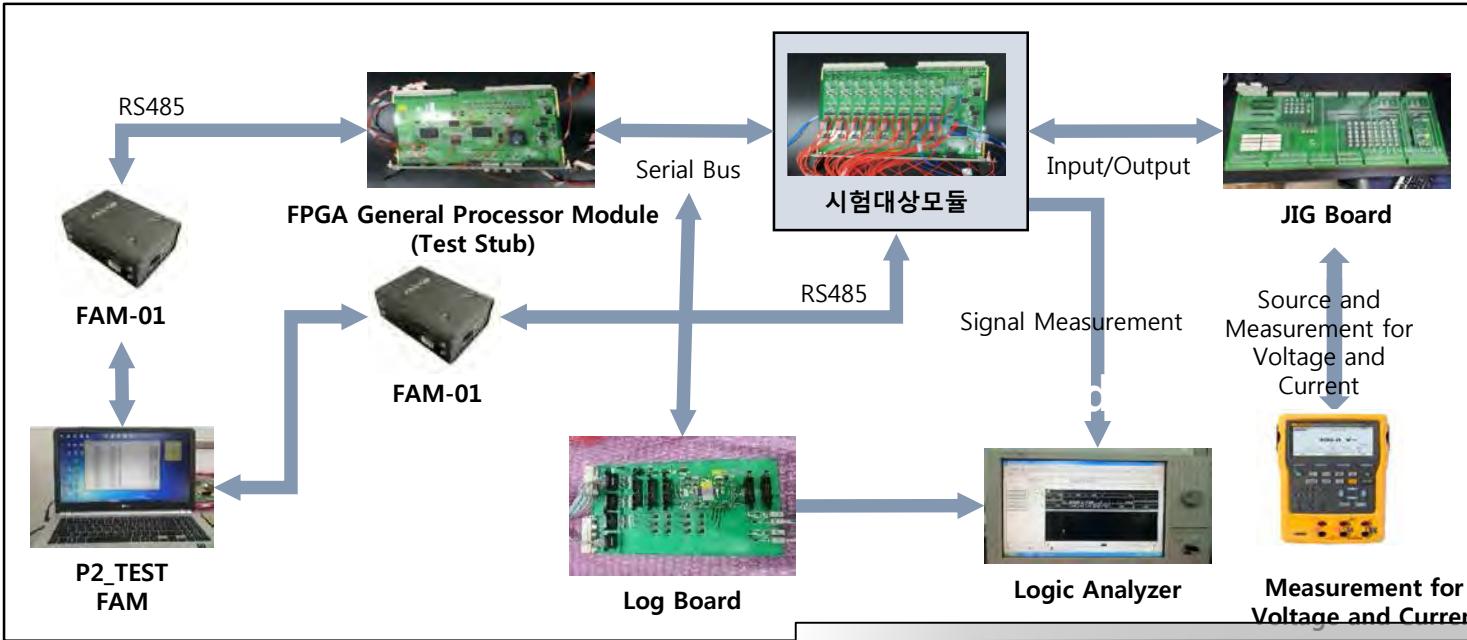
System (FPGA controller) Test

- FPGA verification using hardware signal triggering and monitoring
- Test criteria : Requirement coverage
- Test environment : Jig board and signal jumpers for monitoring



2. V&V and Testing

2-3. Integration Test



◀ Test Environment for I/O Module Integration Test

The Execution for I/O Module Integration Test ▶



2. V&V and Testing

2-4. System Test

Requirement Verification

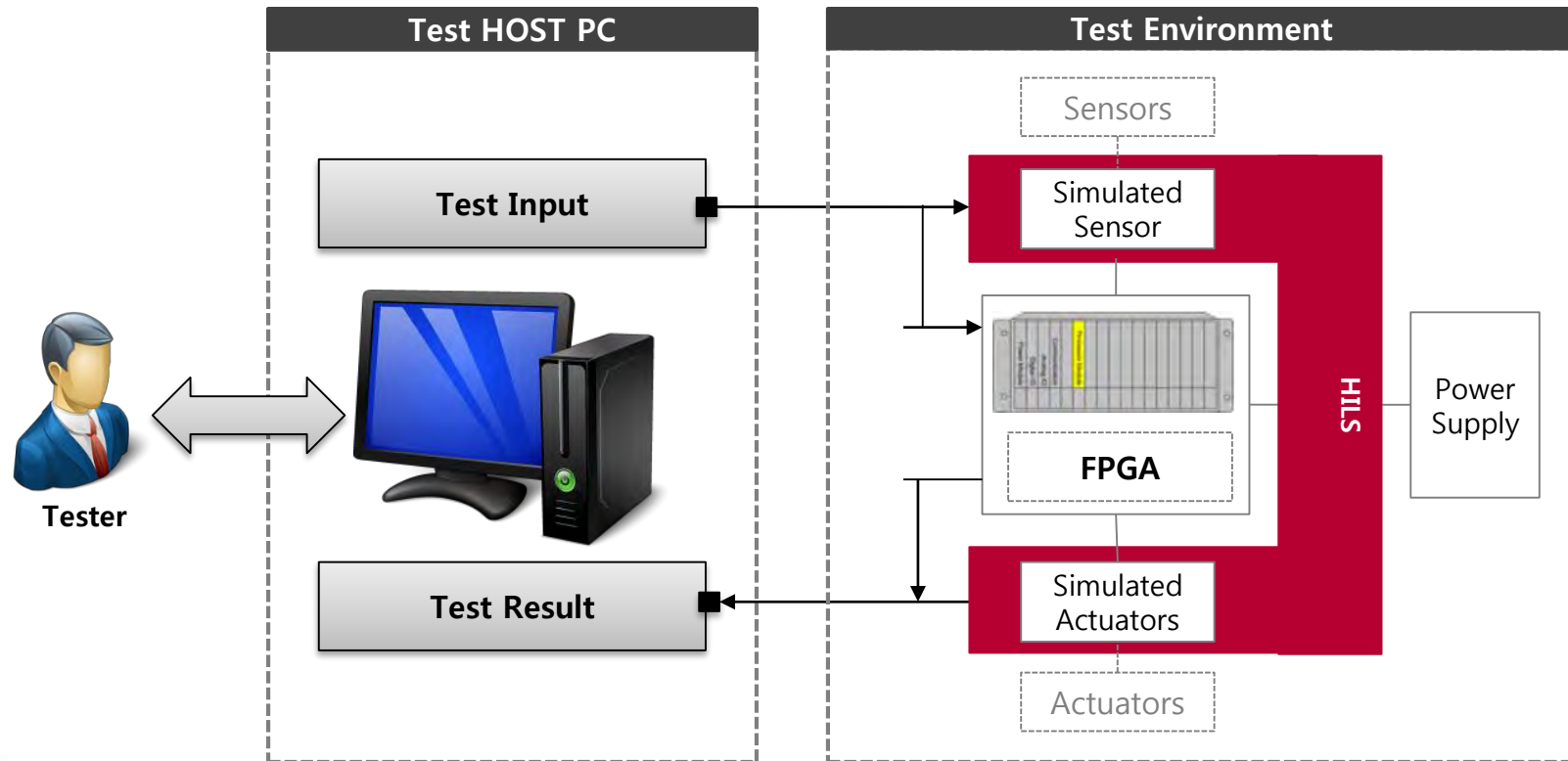
Design Verification

Code Inspection / Component Test

Integration (card, module) Test

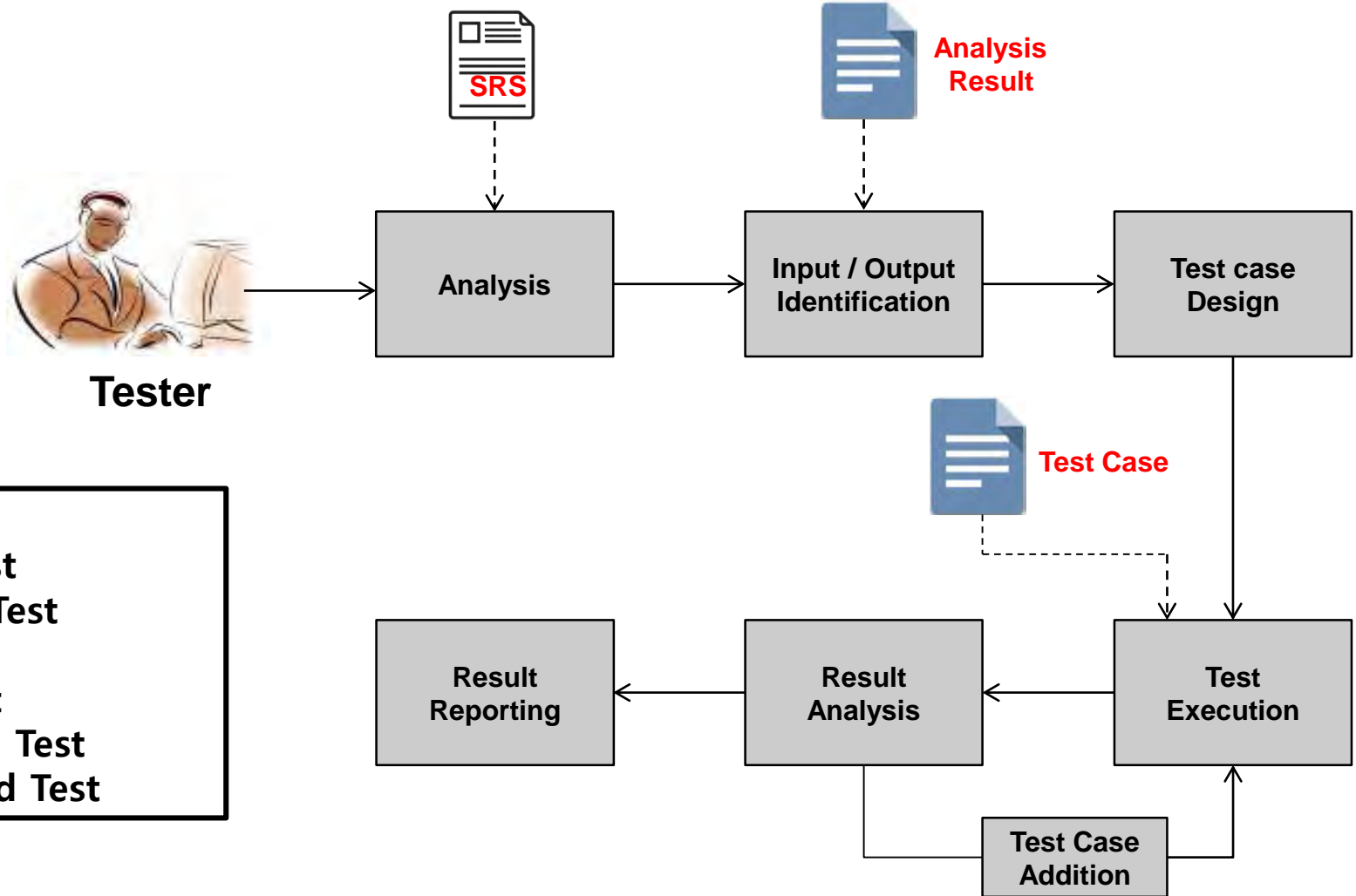
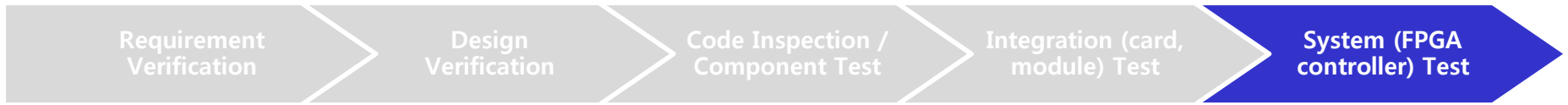
System (FPGA controller) Test

- Validated by Hardware-in-the-loop simulation
- Test criteria : Requirement coverage
- Test environment : Hardware-in-the-loop simulation environment



2. V&V and Testing

2-4. System Test



- System Test
 - Functional Test
 - Performance Test
 - Interface Test
 - Real-time Test
 - Fault Injection Test
 - Scenario based Test

2. V&V and Testing

2-4. System Test



1. Platform Qualification

- $Y=aX$ Linear Function : Full Range Test (10,000)

2. Manual Test before Automatic Testing

- Fluke 754, Graphic Record

3. I/O Combination Test (AI-AO, DI-DO, DI-FDL-GP-F D L-DO)

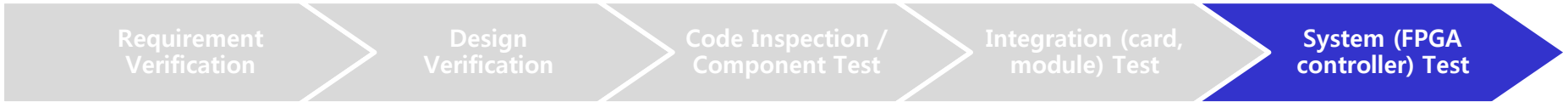
4. Scenario based automatic testing after Satisfying of 1,2 and 3 conditions

- 1) Functional (Triangle Wave : 0-Increment-peak-decrement-0) : 10,000 Test Case
- 2) Performance (Input:25ms –GP –output:50ms : Closed Loop BACK PASS/FAIL)
- 3) Real-time (2ms~1000ms :25ms, 50ms, 500ms etc.)
- 4) Accuracy : 0.01% tolerance

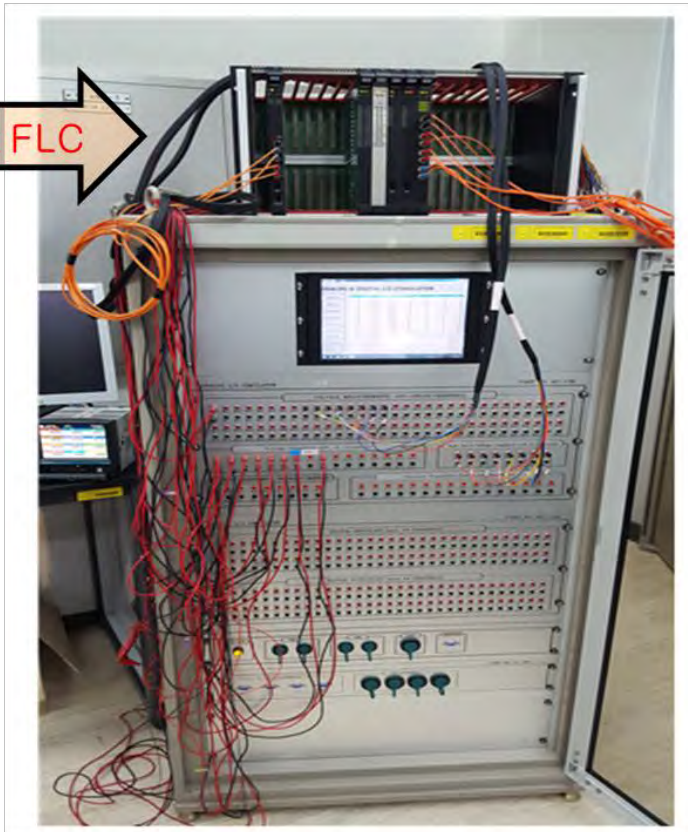
5. Analysis of Test Result

2. V&V and Testing

2-4. System Test

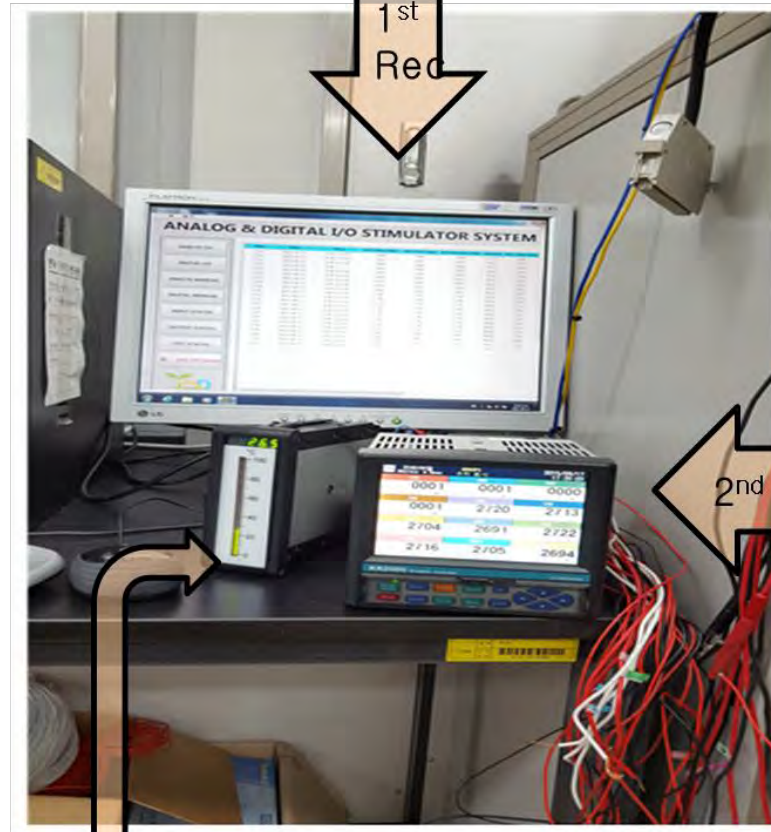


Target FLC



Automatic Signal Generator

1st Rec



2nd REC

Test Result

Table of Contents

1. Introduction

- . V&V in FPGA Development Process
: NUREG/CR-7006, IEC62566

2. V&V and Testing

- . Document Evaluation and Static Verification
- . Component Test
- . Integration Test
- . System Test

3. Recommendation

3. Recommendation

- ◆ ***Let's share practice & ideas for peaceful use of Nuclear Energy***
 - ***Objective/Mission of IAEA, President D. Eisenhower***
- ◆ ***To lead Nuclear Renaissance again***



Thank you for listening

DOOSAN Heavy Industries & Construction



Doosan Heavy Industries & Construction